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INTERNATIONAL IEEE Std 1800.2TM

SystemVerilog – Part 2: Universal Verification Methodology Language Reference Manual





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Contents

1. Overview		12
1.1 Scope		12
1.2 Purpose		
1.3 Word usage		
1.4 Conventions used		
2. Normative references		14
2. Normative references		1.
3. Definitions, acronyms, and abbreviations		
3.1 Definitions		
3.2 Acronyms and abbreviations		16
4. Universal Verification Methodology (UVM) class reference		17
5. Base classes		18
5.1 Overview		18
5.2 uvm void		19
5.3 uvm_object		
5.4 uvm_transaction.		
5.5 uvm_port_base #(IF)		31
5.5 uvm_port_base #(IF) 5.6 uvm_time		34
5.7 uvm_field_op		
6.1 Overview		35
61 Overview		38
6.2 uvm_report_message		30
6.3 uvm_report_object		
6.4 uvm_report_handler		
6.5 Report server.		5(
6.6 uvm report catcher	1	53
	_	
7. Recording classes		58
7.1 uvm_tr_database		59
7.2 uvm_tr_stream		61
7.3 UV \overline{M} links		
8. Factory classes		69
8.1 Overview		69
8.2 Factory component and object wrappers	<u> </u>	69
8.3 UVM factory		75
9. Phasing	Č/	
9.1 Overview		
9.2 Implementation		
9.3 Phasing definition classes		
9.4 uvm_domain		
9.5 uvm_bottomup_phase		
9.6 uvm_task_phase		
9.7 uvm topdown phase		
9.8 Predefined phases		
7.6 Tredefined phases		
10. Synchronization classes		
10.1 Event classes		

10.2 uvm_event_callback		
10.3 uvm_barrier		
10.4 Pool classes		
10.5 Objection mechanism		
10.6 uvm_heartbeat		
10.7 Callbacks classes		
11. Container classes		
11.1 Overview		
11.2 uvm_pool #(KEY,T)		116
11.3 uvm_queue #(T)		118
12. UVM TLM interfaces		120
12.1 Overview		
12.2 UVM TLM 1		120
12.3 UVM TLM 2		
13. Predefined component classes		
13.1 uvm component		
13.2 uvm_test		
13.3 uvm env		
13.4 uvm_agent		
13.5 uvm_monitor		
13.6 uvm scoreboard		
13.7 uvm_driver #(REO RSP)		
13.8 uvm push driver #(REQ,RSP)		
13.8 uvm_push_driver #(REQ,RSP) 13.9 uvm_subscriber	•	176
14. Sequence classes14.1 uvm_sequence_item	-L.	177
14 1 uvm sequence item		177
14.2 uvm_sequence_base		
14.3 uvm_sequence #(REQ,RSP)		
14.4 uvm_sequence_library		
15. Sequencer classes	0	10
15.1 Overview		
15.1 Overview		
15.2 Sequencer interface 15.3 uvm_sequencer_base		
15.5 uvin_sequencer_oase		
15.5 uvm_sequencer #(REQ,RSP) 15.6 uvm_push_sequencer #(REQ,RSP)		
	6	
16. Policy classes	<u></u>	
16.1 uvm_policy		
16.2 uvm_printer		
16.3 uvm_comparer		
16.4 uvm_recorder		
16.5 uvm_packer		
16.6 uvm_copier		
17. Register layer		
17.1 Overview		
17.2 Global declarations		
		251
9 Degrater model		

18.2 uvm_reg_map	
18.3 uvm reg file	
18.4 uvm reg	
18.5 uvm reg field.	
18.6 uvm mem	
18.7 uvm reg indirect data	
18.7 uvm_reg_fifo	
18.9 uvm_vreg	
18.10 uvm_vreg_field	
18.11 uvm_reg_cbs	
18.12 uvm_mem_mam	
19. Register layer interaction with the design	347
19.1 Generic register operation descriptors	
19.2 Classes for adapting between register and bus operations	
19.3 uvm_reg_predictor	
19.4 Register sequence classes	
19.5 uvm_reg_backdoor	
19.6 UVM HDL backdoor access support routines	
Annex A (informative) Bibliography	367
Annex B (normative) Macros and defines	
B.1 Report macros	
B.2 Utility and field macros for components and objects	
B.3 Sequence-related macros.	
B.4 Callback macros	
B.5 UVM TLM implementation port declaration macros	
B.6 Size defines	
B.7 UVM version globals	
Annex C (normative) Configuration and resource classes	
C.1 Overview	
C.2 Resources	
C.3 UVM resource database	401
C.3 UVM resource database C.4 UVM configuration database	404
Annex D (normative) Convenience classes, interface, and methods	407
D.1 uvm_callback_iter	
D.2 Component interfaces	
D.3 uvm_reg_block access methods	
D.3 uvm_reg_block access methods D.4 Callback typedefs	
D.4 Callback typedefs	414
D.4 Callback typedefs Annex E (normative) Test sequences	
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq	
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences	
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences	
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences	
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences	
D.4 Callback typedefs. Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences E.6 Memory walking-ones test sequences	414 416 416 416 418 420 422 423
D.4 Callback typedefs Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences	414 416 416 416 418 420 422 423
D.4 Callback typedefs. Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences E.6 Memory walking-ones test sequences	
D.4 Callback typedefs. Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences E.6 Memory walking-ones test sequences E.7 uvm_reg_mem_hdl_paths_seq E.8 uvm_reg_mem_built_in_seq	
D.4 Callback typedefs. Annex E (normative) Test sequences E.1 uvm_reg_hw_reset_seq E.2 Bit bashing test sequences E.3 Register access test sequences E.4 Shared register and memory access test sequences E.5 Memory access test sequences E.6 Memory walking-ones test sequences E.7 uvm_reg_mem_hdl_paths_seq	

°ore service °raversal vm_run_test_callback	
viii_tuii_tust_calluauk	
vm_root	
(normative) Command line arguments	
Command line processing Built-in UVM-aware command line arguments	
unt-in O vivi-aware command fine arguments	
(normative) Deprecation	
eneral	
onstructs that have been deprecated	
informative) Participants	

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0	1800.2 (2020)	91/1872/FDIS	91/1886/RVD

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Approved 4 June 2020

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Accellera Systems Initiative-The Universal Verification Methodology (UVM) Pre-IEEE Class Reference.

Abstract: The Universal Verification Methodology (UVM) that can improve interoperability, reduce the cost of using intellectual property (IP) for new projects or electronic design automation (EDA) tools, and make it easier to reuse verification components is provided. Overall, using this standard will lower verification costs and improve design quality throughout the industry. The primary audiences for this standard are the implementors of the UVM base class library, the implementors of tools supporting the UVM base class library, and the users of the UVM base class library.

g. ca. . 1800.2.¹ . uencer, tran. Keywords: agent, blocking, callback, class, component, consumer, driver, event, export, factory, function, generator, IEEE 1800.2[™], member, method, monitor, non-blocking, phase, port, register, resource, sequence, sequencer, transaction-level modeling, verification methodology

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Introduction

This introduction is not part of IEEE Std 1800.2[™]-2020, IEEE Standard for Universal Verification Methodology Language Reference Manual.

Verification has evolved into a complex project that often spans internal and external teams, but the discontinuity associated with multiple, incompatible methodologies among those teams can limit productivity. The Universal Verification Methodology (UVM) Language Reference Manual (LRM) addresses verification complexity and interoperability within companies and throughout the electronics industry for both novice and advanced teams while also providing consistency. While UVM is revolutionary, being the first verification methodology to be standardized, it is also evolutionary, as it is built on the Open Verification Methodology (OVM), which combined the Advanced Verification Methodology (AVM) with the Universal Reuse Methodology (URM) and concepts from the e Reuse Methodology (eRM). Furthermore, UVM also infuses concepts and code from the Verification Methodology Manual (VMM), plus the collective experience and knowledge of the over 300 members of the Accellera UVM Working Group to help standardize verification methodology. Finally, the transaction-level modeling (TLM) facilities in UVM are based on what was re. Josephary. developed by Open SystemC Initiative (OSCI) for SystemC, though they are not an exact replication or reimplementation of the SystemC TLM library.

IEEE Standard for Universal Verification Methodology Language Reference Manual

1. Overview

1.1 Scope

This standard establishes the Universal Verification Methodology (UVM), a set of application programming interfaces (APIs) that defines a base class library (BCL) definition used to develop modular, scalable, and reusable components for functional verification environments. The APIs and BCL are based on the IEEE standard for SystemVerilog, IEEE Std 1800^{TM, 1}

1.2 Purpose

Verification components and environments are currently created in different forms, making interoperability among verification tools and/or geographically dispersed design environments both time consuming to develop and error prone. The results of the UVM standardization effort will improve interoperability and reduce the cost of repurchasing and rewriting intellectual property (IP) for each new project or electronic design automation (EDA) tool, as well as make it easier to reuse verification components. Overall, the UVM standardization effort will lower verification costs and improve design quality throughout the industry.

1.3 Word usage

The word *shall* indicates mandatory requirements strictly to be followed in order to conform to the standard and from which no deviation is permitted (*shall* equals *is required to*).^{2, 3}

The word *should* indicates that among several possibilities one is recommended as particularly suitable, without mentioning or excluding others; or that a certain course of action is preferred but not necessarily required *(should* equals *is recommended that)*.

The word *may* is used to indicate a course of action permissible within the limits of the standard (*may* equals *is permitted to*).

The word *can* is used for statements of possibility and capability, whether material, physical, or causal (*can* equals *is able to*).

¹ Information on references can be found in Clause $\underline{2}$.

 $^{^{2}}$ The use of the word *must* is deprecated and cannot be used when stating mandatory requirements, *must* is used only to describe unavoidable situations.

³ The use of *will* is deprecated and cannot be used when stating mandatory requirements, *will* is only used in statements of fact.

1.4 Conventions used

The conventions used throughout the document are as follows:

UVM is case-sensitive.

Any syntax examples shown in this standard are informative. They are intended to illustrate the usage of UVM constructs in a simple context and do not define the full syntax.

1.4.1 Visual cues (meta-syntax)

Bold shows required keywords and/or special characters, e.g., uvm_component.

Italics shows variables or definitions, e.g., name or Globals.

courier shows SystemVerilog examples, external command names, directories and files, etc., e.g., an implementation needs to call super.do copy.

The asterisk (*) symbol, when combined with a prefix and/or postfix denoting a part of the construct, represents a series of construct names with exactly this prefix and/or postfix, e.g., class uvm * port.

1.4.2 Return values

- Equivalent terms: a)
 - "TRUE," "True," and "true" are equivalent to each other and used interchangeably throughout 1) this document.
 - "FALSE," "False," and "false" are equivalent to each other and used interchangeably throughout 2) this document.
- A bit value of 1 is treated as TRUE and 0 is treated as FALSE. b)
- Conversely, TRUE refers to 1 and FALSE refers to 0 for return values. c)
- Datatypes returned: d)
 - For a bit or integer, 1 (or 1'b1) or 0 (1'b0) is acceptable. 1)
 - 2) For an enumerated type, TRUE or FALSE is acceptable.
- For functions that return TRUE/FALSE, if only one returned value is defined (e.g., for TRUE), then the e) opposite return value shall be inferred (for all other possibilities).

1.4.3 Inheritance

Class declarations shown in this document may be of the form *class A* extends *B*. These declarations do not imply class A and class B are adjacent in the inheritance tree; implementations are free to have other classes between A and B in the inheritance tree, e.g., 2 12 5

```
class X extends B;
 // body of class X
endclass
class A extends X;
  // body of class A
endclass
```

would comply.

The API and the semantics of the API from a base class shall be present in any derived classes, unless that API is overridden by an explicitly documented API within the derived class.

1.4.4 Operation order on equivalent data objects

The functionality described in this document typically operates on a set of data objects. An implementation and/or the underlying run-time engine may choose any operation order or sorting order for "equivalent data" objects within the specified semantics.

As a result of this policy, results returned and/or sequential behavior and/or produced output may differ between implementations and/or different underlying engines.

It is up to the user to establish an operation order if necessary.

1.4.5 uvm_pkg

All properties of UVM, including classes, global methods, and variables, are exported via the uvm pkg package. They may be accessed via import or via the Scope Resolution Operator (::).

UVM does not require any specific time unit precision for uvm pkg.

All UVM methods that operate on values of type time, such as **uvm_printer::print_time** (see <u>16.2.3.11</u>), are subject to the time scaling defined in IEEE Std 1800[™].

1.4.6 Random stability

Any APIs that result in user code being executed are not guaranteed to be random stable. All other APIs are guaranteed to be random stable, unless otherwise specified.

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The following referenced documents are indispensable for the application of this document (i.e., they must be understood and used, so each referenced document is cited in text and its relationship to this document is explained). For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments or corrigenda) applies.

- 15 -

IEEE Std 1800TM, IEEE Standard for SystemVerilog—Unified Hardware Design, Specification, and Verification Language.^{4, 5}

3. Definitions, acronyms, and abbreviations

For the purposes of this document, the following terms and definitions apply. The *IEEE Standards Dictionary Online* should be consulted for terms not defined in this clause.⁶

3.1 Definitions

agent: An abstract container used to emulate and verify device under test (DUT) devices; agents encapsulate a **driver**, **sequencer**, and **monitor**.

blocking: An interface where tasks block execution until they complete. See also: non-blocking.

component: A piece of verification intellectual property (VIP) that provides functionality and interfaces.

consumer: A verification component that receives transactions from another component.

driver: A component responsible for executing or otherwise processing **transactions**, usually interacting with the device under test (DUT) to do so.

environment: The container object that defines the testbench topology.

export: A transaction-level modeling (TLM) interface that provides an implementation of methods used for communication. Used in Universal Verification Methodology (UVM) to connect to a port.

factory method: A classic software design pattern used to create generic code by deferring, until run time, the exact specification of the object to be created.

hook: A method that enables users to customize certain behaviors of a component.

generator: A verification **component** that provides transactions to another **component**. Also referred to as a *producer*.

monitor: A passive entity that samples device under test (DUT) signals, but does not drive them.

non-blocking: A call that returns immediately. See also: blocking.

policy: A collection of settings used to apply an operation to a class.

port: A transaction-level modeling (TLM) interface that defines the set of methods used for communication. Used in Universal Verification Methodology (UVM) to connect to an export.

proxy: A class functioning as an interface to another component or class.

request: A transaction that provides information to initiate the processing of a particular operation.

response: A transaction that provides information about the completion or status of a particular operation.

⁵ The IEEE standards or products referred to in Clause 2 are trademarks owned by the Institute of Electrical and Electronics Engineers, Incorporated.

⁴ IEEE publications are available from the Institute of Electrical and Electronics Engineers (http://standards.ieee.org/).

⁶ IEEE Standards Dictionary Online is available at: <u>http://ieeexplore.ieee.org/</u>.